



A UVM Testbench for Exploring Design Margins of Analog/Mixed-Signal Systems: A PCI-Express Receiver Detection Circuit Example

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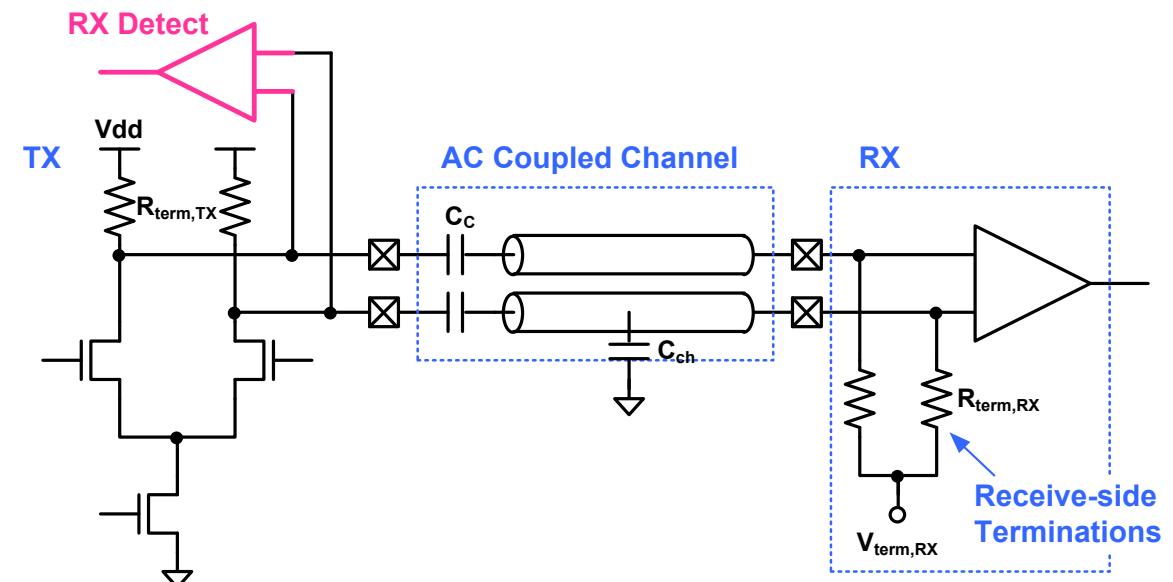
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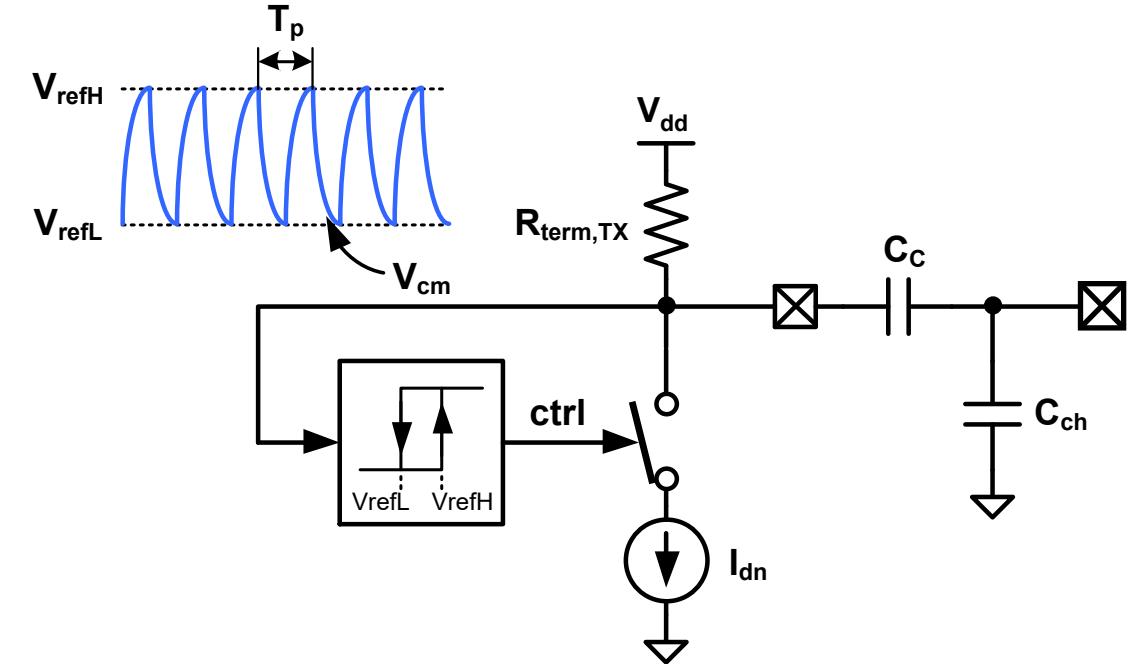
PCIe Receiver Detection Circuit

- A PCIe transmitter (TX) needs to determine whether a receiver (RX) is connected before initiating data transmission
- The receiver detection circuit must function correctly for a range of condition parameters:
 - AC coupling capacitance (C_c) : 76~265nF
 - Equiv. channel capacitance (C_{ch}) : 0~3nF
 - TX-side termination ($R_{term,TX}$) : 40~60Ω
 - RX-side termination ($R_{term,RX}$) : 40~60Ω



RX Detection Circuit Example: Idea

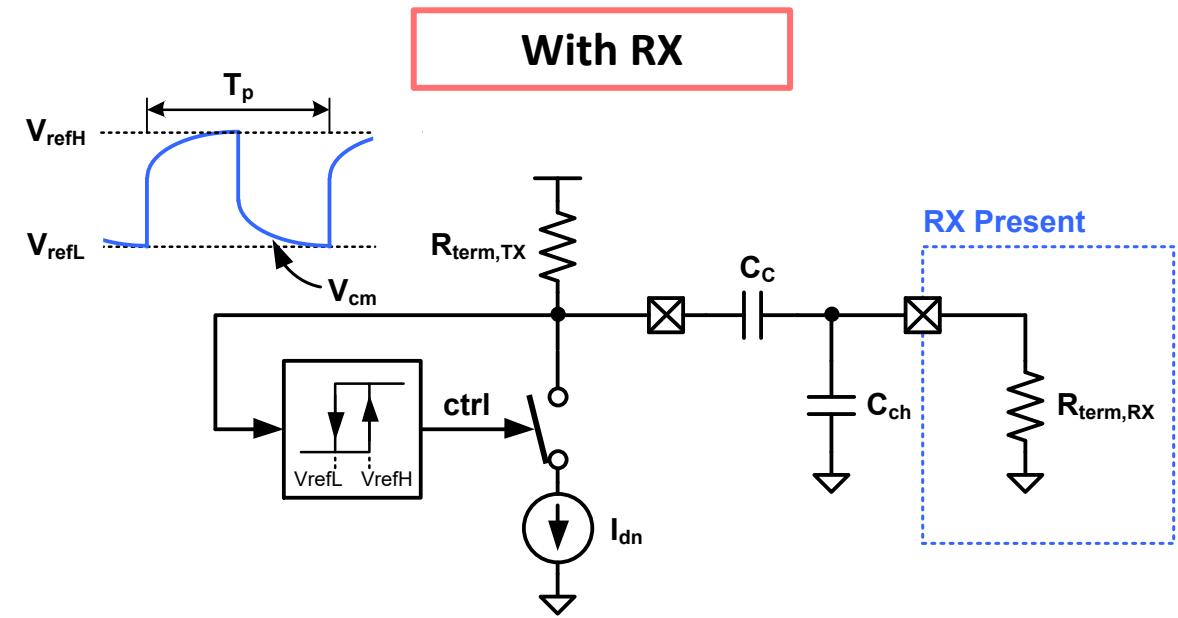
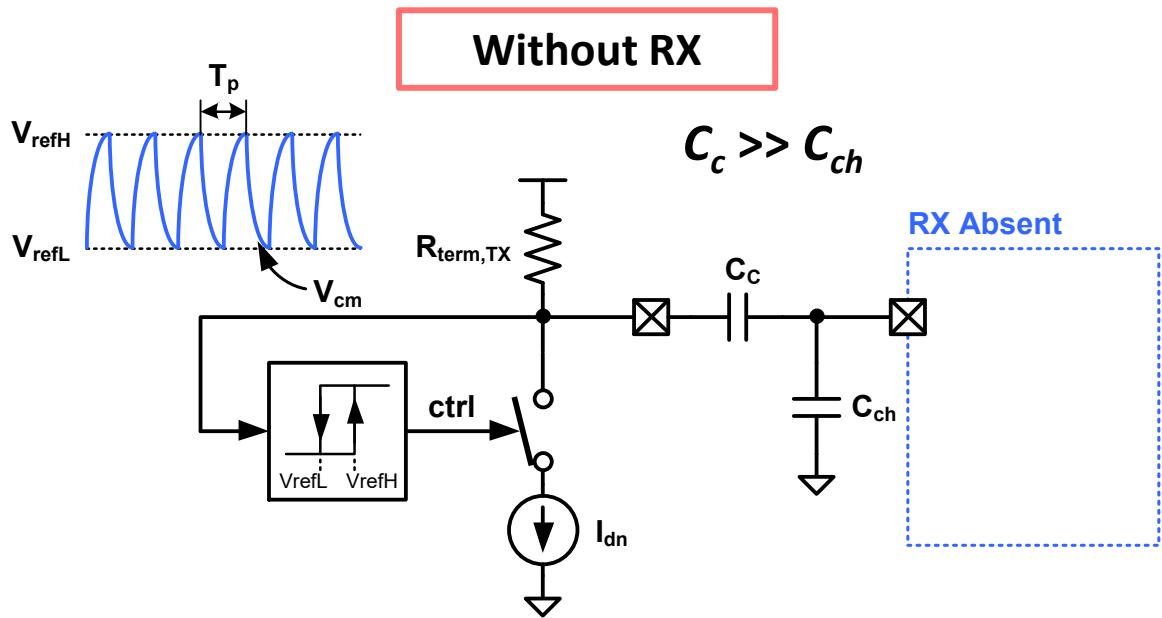
- Transforms the transmitter into a relaxation oscillator and measures its oscillation period
 - With the TX pull-down current (I_{dn}) off, the TX common-mode output (V_{cm}) rises toward the supply voltage V_{dd}
 - When V_{cm} reaches $V_{ref,H}$, I_{dn} is switched on and V_{cm} starts falling
 - When V_{cm} reaches $V_{ref,L}$, I_{dn} is switched off and V_{cm} starts rising again



[2] C. Guo and F. Yang, "Method and Apparatus for Receiver Detection on a PCI-Express Bus", US Patent US7222290B2.

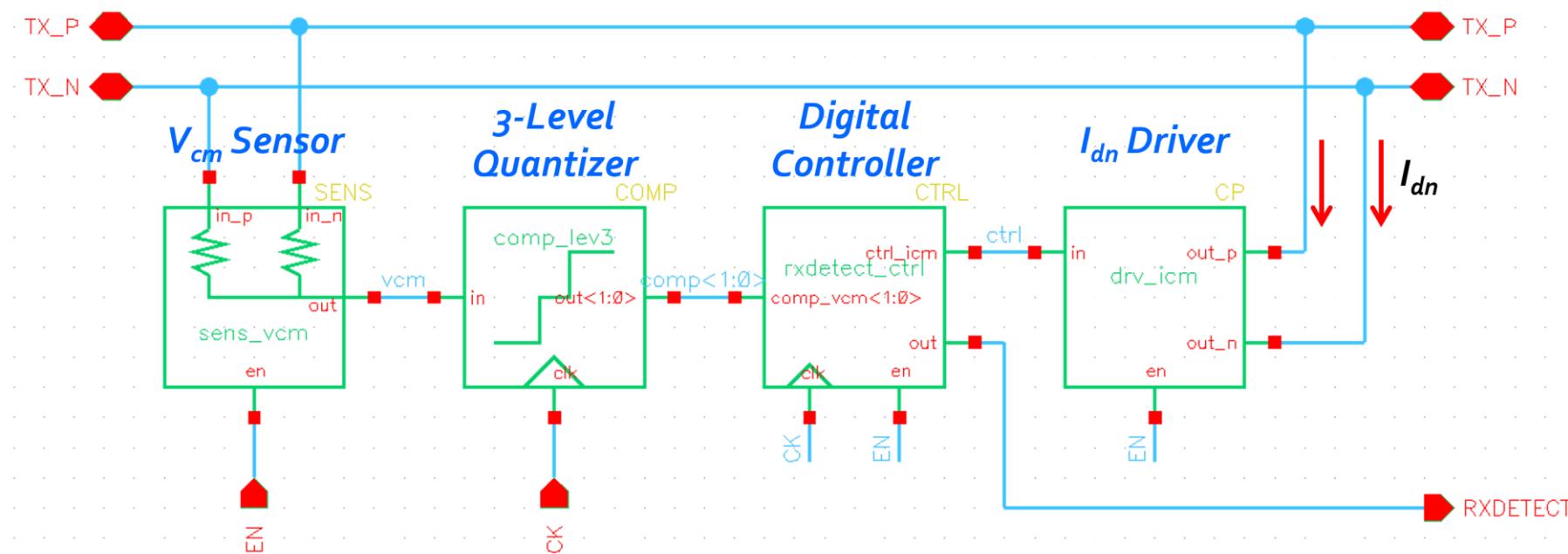
RX Detection Circuit Operation

- The presence of RX can be detected based on the oscillation period
 - Without RX present: V_{cm} settles with $\tau_{w/oRX} \approx R_{term,TX} \cdot C_{ch} \rightarrow \text{short periods}$
 - With RX present: V_{cm} settles with $\tau_{w/RX} \approx (R_{term,TX} + R_{term,RX}) \cdot C_c \rightarrow \text{long periods}$



RX Detection Circuit Implementation

- The RX detection circuit is a mixed-signal feedback loop with 4 components
 - A digital controller is inserted to measure the oscillation period in digital counts (N_p)
 - A receiver is considered to be present when $N_p > N_{p,thres}$

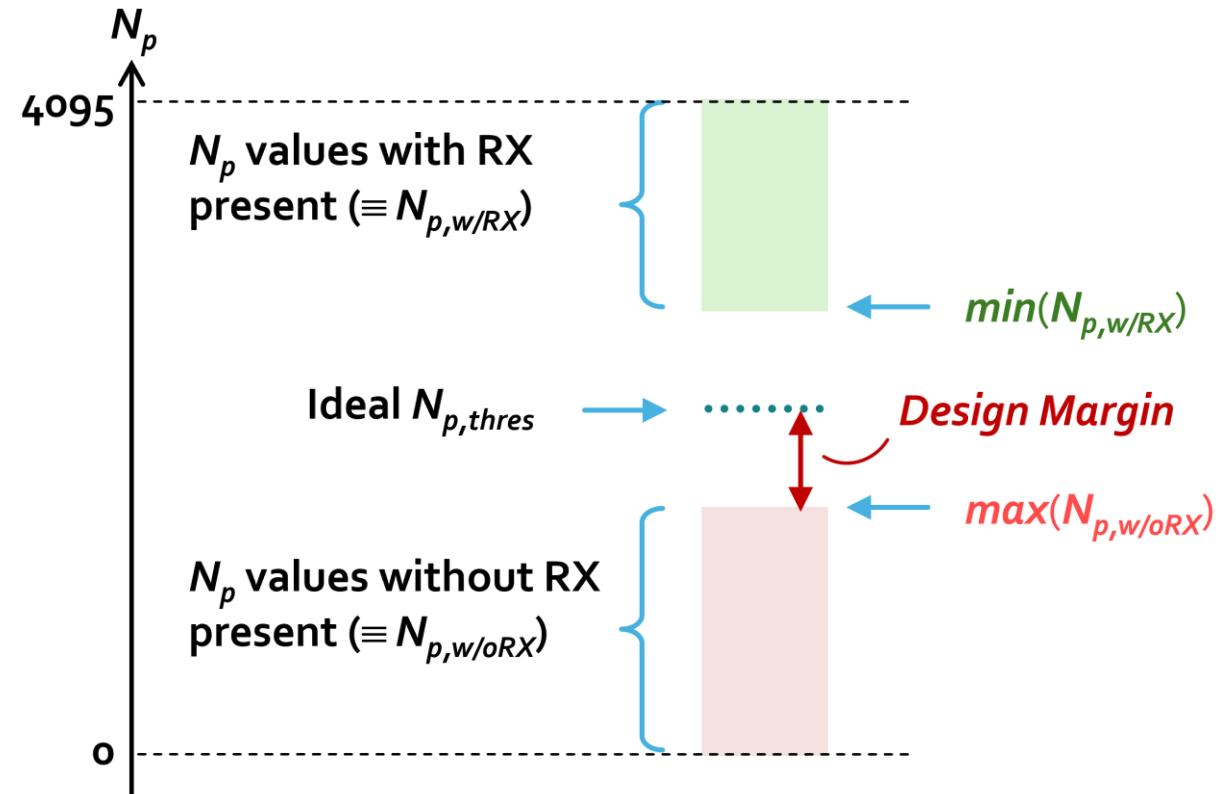


Design Margins of RX Detection Circuit

- The RX detection circuit must operate correctly for a range of condition parameter values:

$(C_c, C_{ch}, R_{term,TX}, R_{term,RX})$

- It implies that the oscillation period count (N_p) will vary as well
- Minimum N_p with RX** must be sufficiently greater than **maximum N_p without RX**
- $\min(N_{p,w/RX}) > \max(N_{p,w/oRX})$



Goal of This Work

- Build a UVM testbench that can characterize the design margin of a PCIe receiver detection circuit
 - What is the **min. N_p value with RX** across the range of condition parameters?
 - What is the **max. N_p value without RX** across the range of condition parameters?
- To achieve this, we need to:
 - Model the analog components of the PCIe transceiver in SystemVerilog; and
 - Find the min/max values of N_p by exploring a continuous-valued parameter space

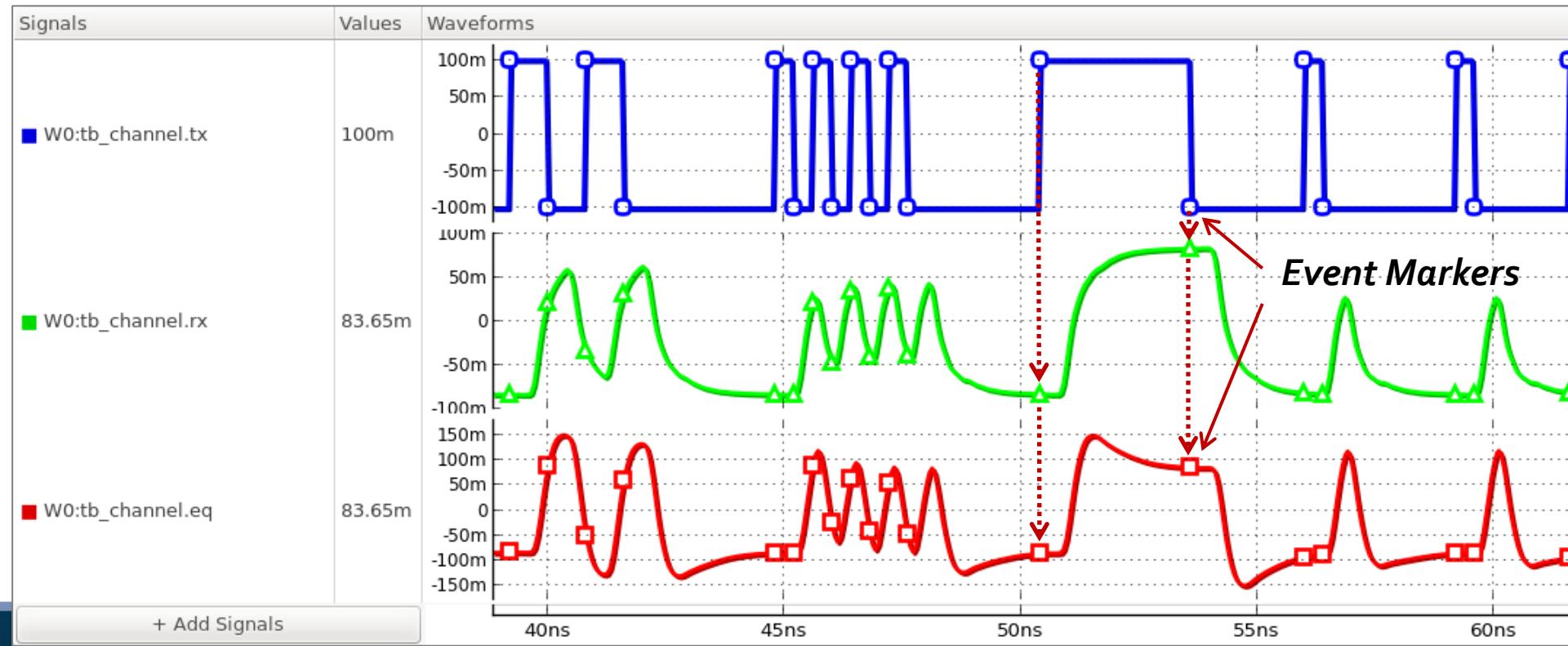
XMODEL Enables Analog in SystemVerilog/UVM

- XMODEL is a plug-in extension enabling *fast and accurate analog/mixed-signal* simulation in *SystemVerilog*
 - *Event-driven*: delivering 10~100x faster speed than Real-Number Model (RNM)
 - *Analog*: supporting both functional and circuit-level models
 - *SystemVerilog*: fully compliant with SystemVerilog-based flows (e.g. UVM)



Event-Driven Simulation of Analog Circuits

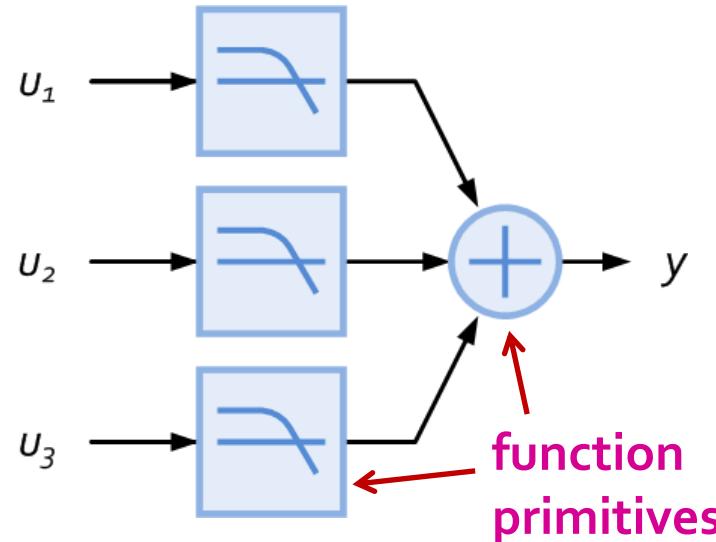
- Using equation-based representation, *XMODEL* performs event-driven simulation of analog circuits in SystemVerilog



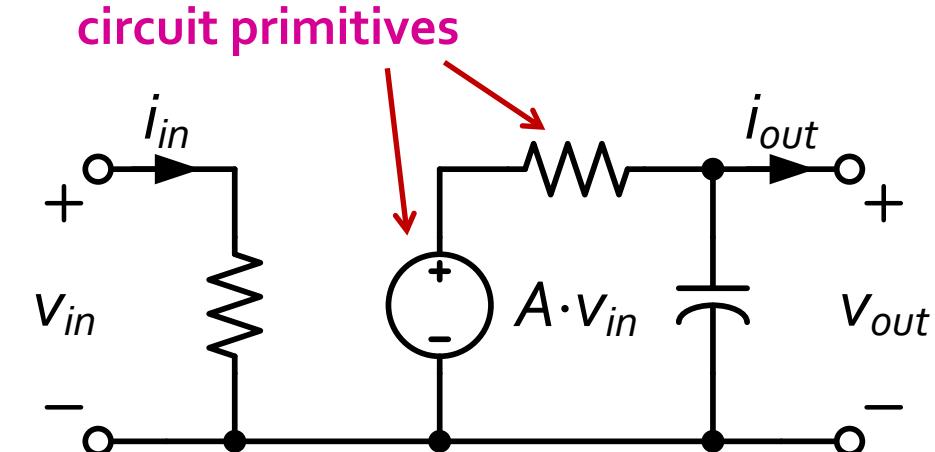
Modeling Analog Circuits with XMODEL Primitives

- One can describe both signal-flow and conservative-system models of analog circuits by combining a rich set of *XMODEL* primitives

Signal-flow Model
(Block-Level Model)



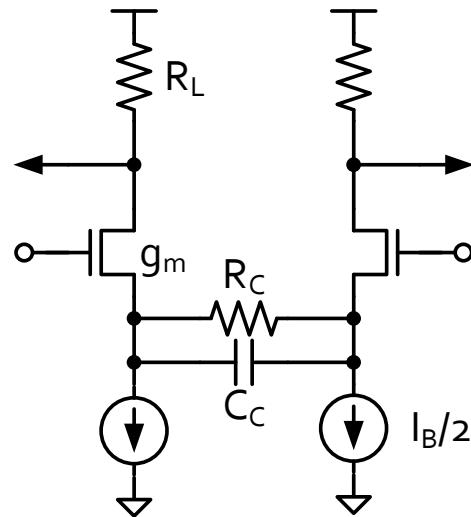
Conservative-System Model
(Circuit-Level Model)



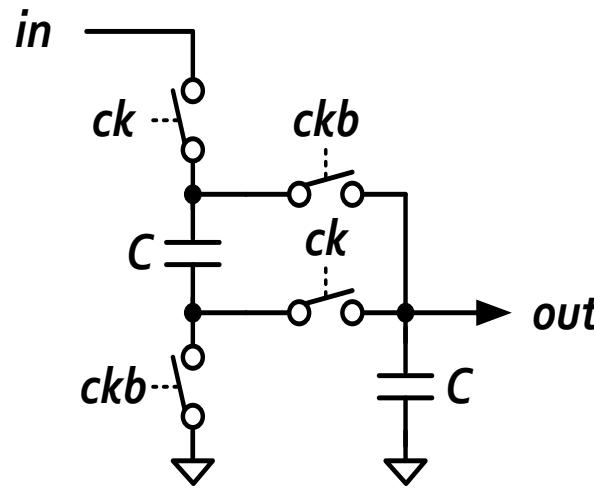
Circuit-Level Modeling with XMODEL

- The circuit primitives of XMODEL allow one to model analog circuits by listing their elements directly in SystemVerilog
 - It's the most natural way to model nonlinear, switching, and loading effects

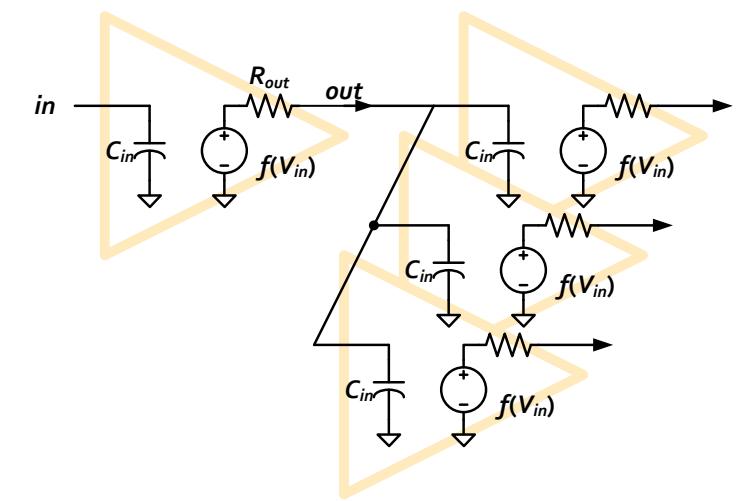
Nonlinear Effects



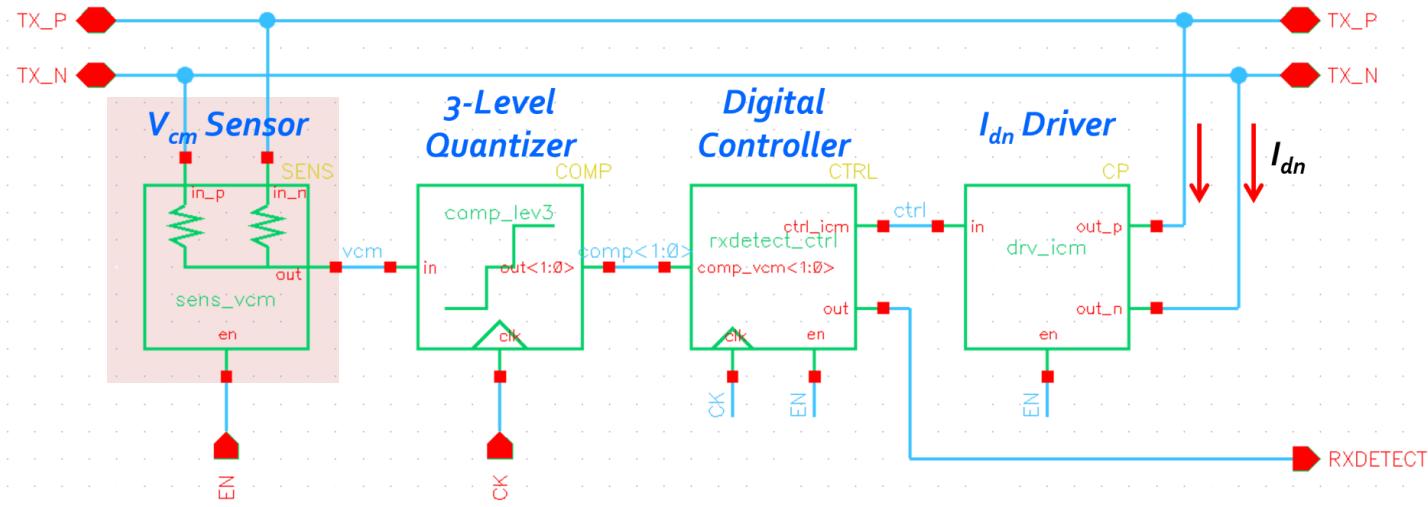
Switching Effects



Loading Effects



RX Detection Circuit Model: V_{cm} Sensor



- V_{cm} sensor measures the common mode of the TX outputs with a pair of resistors when enabled
- Described using ***switch*** primitives

sens_vcm.sv: TX common-mode sensor

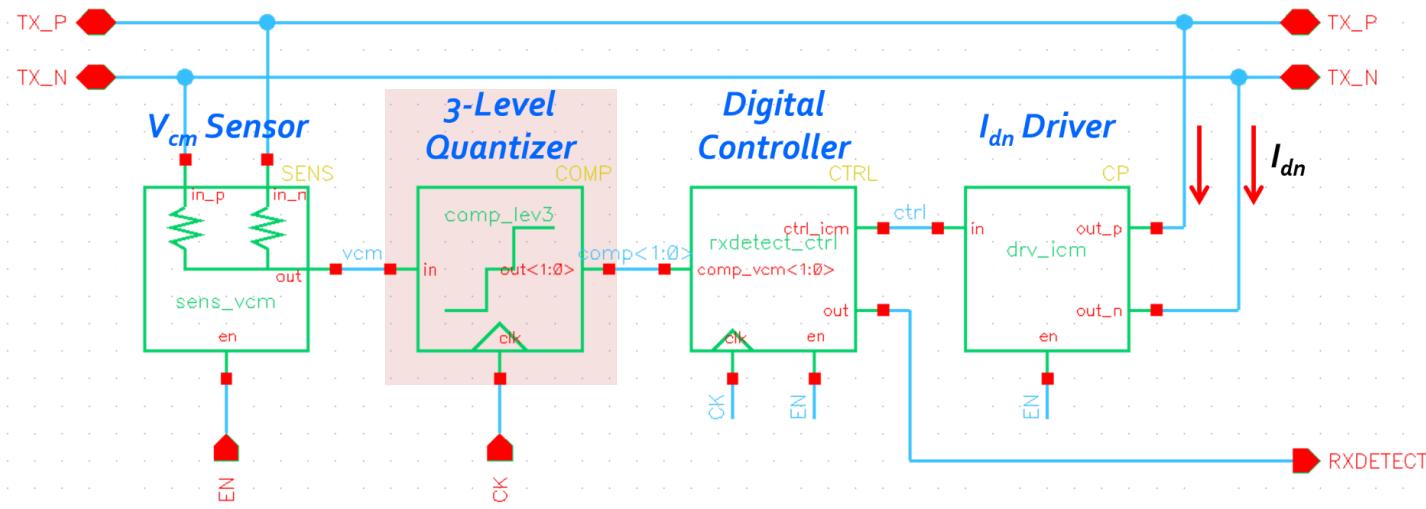
```
module sens_vcm (
    output xreal out,
    input xreal in_p, in_n,
    input xbit en
);

xreal p0, n0;

switch #(.R0(`INFINITY), .R1(10.0e3))
SW1 (.pos(p0), .neg(out), .ctrl(en));
switch #(.R0(`INFINITY), .R1(10.0e3))
SW2 (.pos(n0), .neg(out), .ctrl(en));

endmodule // sens_vcm
```

RX Detection Circuit Model: 3-Level Quantizer



- **Three-level quantizer** digitizes V_{cm} into a 2-bit code 00, 01, 11 by comparing it against V_{refL} and V_{refH}
- Described using **compare** primitives

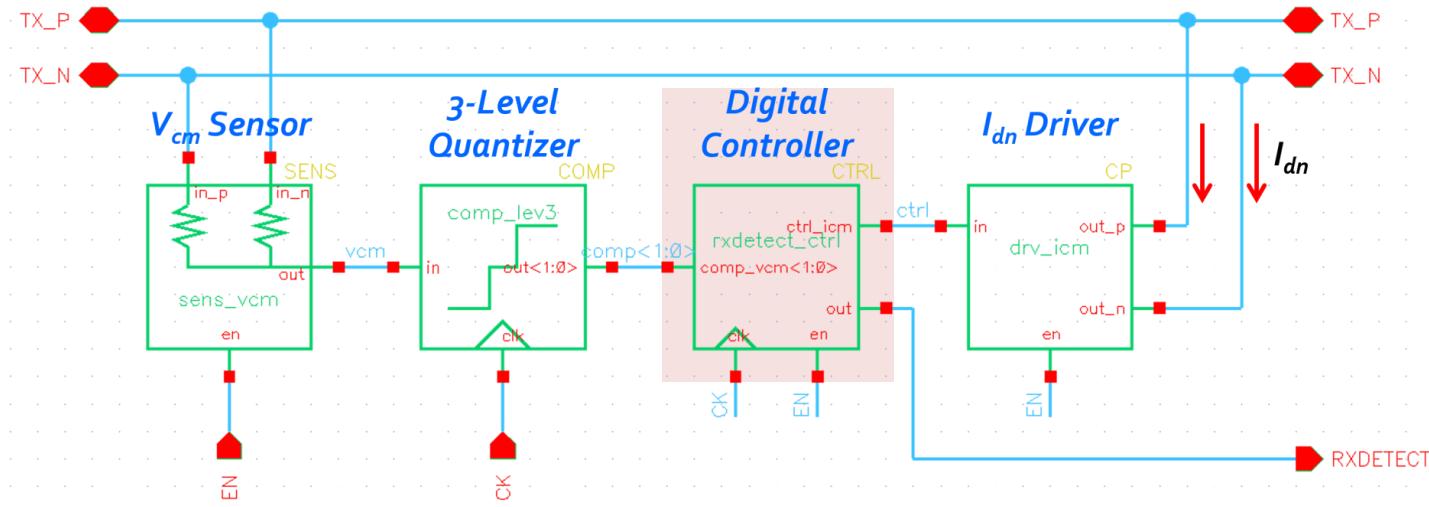
comp_lev3.sv: 3-level quantizer

```
module comp_lev3 #(
    parameter real VrefH = 1.75,
    parameter real VrefL = 1.35
) (
    output xbit [1:0] out,
    input xreal in,
    input xbit clk
);

compare #(threshold(VrefL))
    COMP0 (.out(out[0]), .in(in),
            .in_ref(`ground), .trig(clk));
compare #(threshold(VrefH))
    COMP1 (.out(out[1]), .in(in),
            .in_ref(`ground), .trig(clk));

endmodule // comp_lev3
```

RX Detection Circuit Model: Digital Controller



- **Digital controller** switches the TX currents (I_{dn}) on or off based on the quantizer output and counts N_p
- Described in pure Verilog

rxdetect_ctrl.sv: digital controller

```

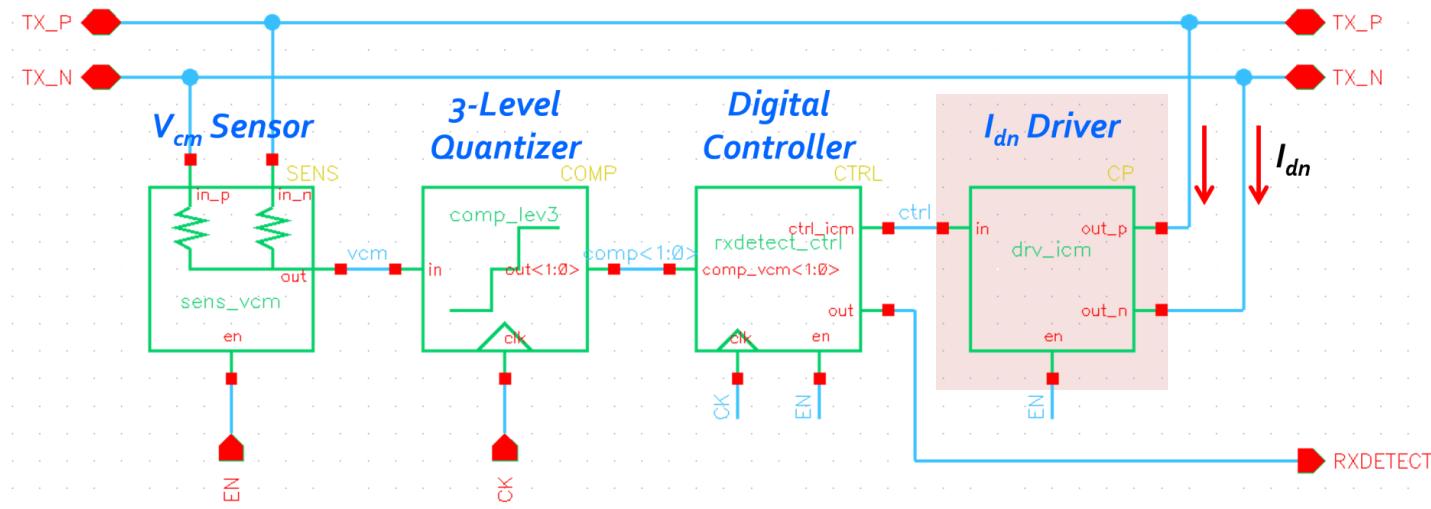
module rxdetect_ctrl #(
    parameter int Np_thres = 1024
)
(
    output reg ctrl_icm, out,
    input [1:0] comp_vcm,
    input clk, en
);
    reg ctrl_prev;
    reg [16:0] Np_cnt, Tp_cnt;
    reg [16:0] out;

    always @(posedge clk) begin
        if (!en) {ctrl_prev, ctrl_icm} <= 2'b00;
        else begin
            ctrl_prev <= ctrl_icm;
            if (comp_vcm == 2'b11) ctrl_icm <= 1;
            else if (comp_vcm == 2'b00) ctrl_icm <= 0;
        end
    end

    always @(posedge clk) begin
        if (!en) {Np_cnt, Tp_cnt, out} <= 16'b0;
        else if (!out) begin
            if (Np_cnt > 0) Tp_cnt <= (Tp_cnt < 12'ffff) ? Tp_cnt + 1 : 12'ffff;
            if (ctrl_prev && !ctrl_icm) begin
                if (Np_cnt < Np) Np_cnt <= Np_cnt + 1;
                else {Np_cnt, Tp_cnt, out} <= (Tp_cnt > Tp_thres) ? 16'b1 : 16'b0;
            end
        end
    end
endmodule

```

RX Detection Circuit Model: TX Current Driver



- **TX current driver** pulls a common-mode current (I_{dn}) from the TX outputs depending on the control input
- Described using ***transition*** & ***isource*** primitives

drv_icm.sv: TX current driver

```
module drv_icm #(
    parameter real Idn = 0.0125
)()
    output xreal out_p, out_n,
    input xbit in, en
);

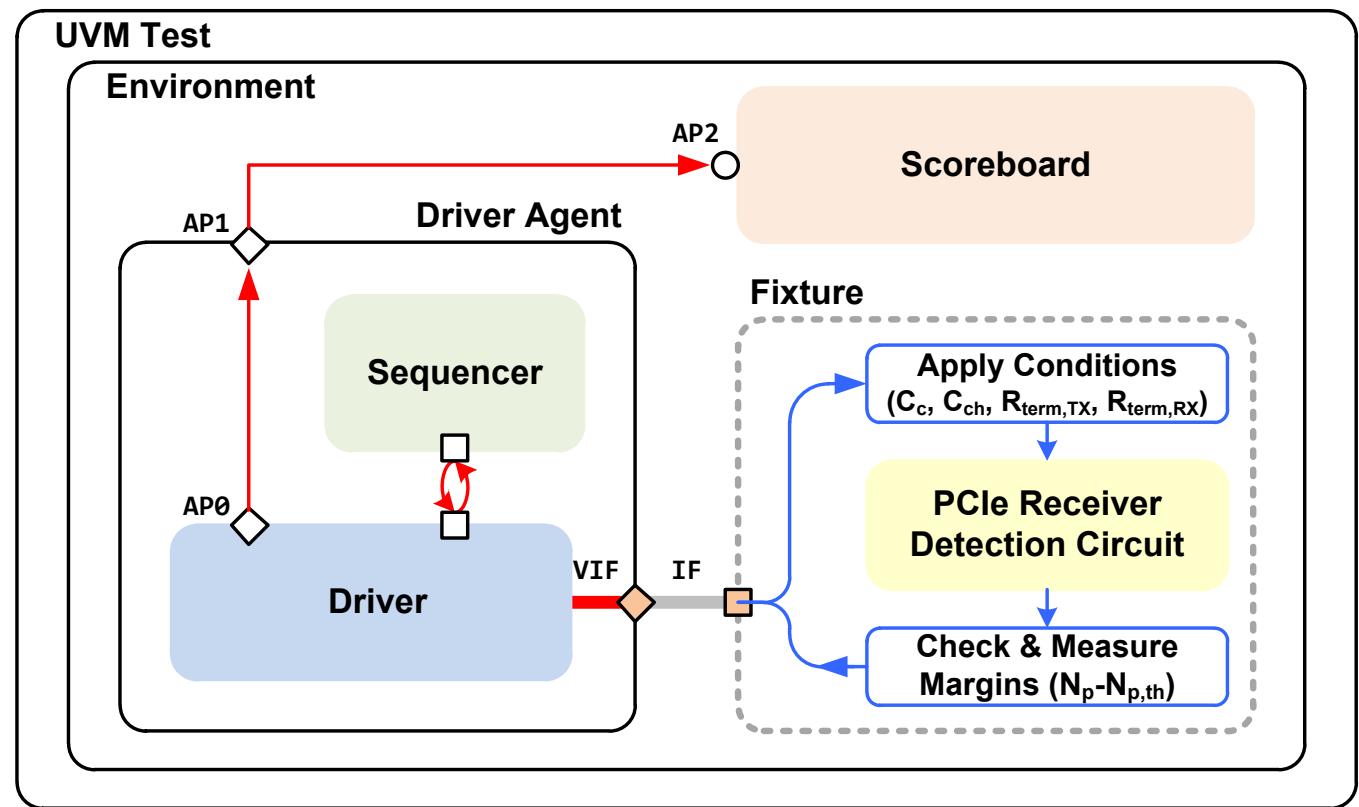
xbit ctrl;

and_xbit U0 (.out(ctrl), .in({in,en}));
transition #( .value0(0.0), .value1(Idn))
U1 (.out(i_dn), .in(ctrl));
isource #(.mode("in"))
IP (.pos(out_p), .neg(`ground), .in(i_dn));
isource #(.mode("in"))
IN (.pos(out_n), .neg(`ground), .in(i_dn));

endmodule // drv_icm
```

UVM Testbench for Design Margin Exploration

- **Driver agent** searches for condition parameters that minimize or maximize N_p
- **Fixture module** applies the condition parameters to the DUT and measures N_p
- **Scoreboard** reports the min. N_p with the receiver present and max. N_p without



Driver Agent

- Driver agent finds the optimal set of C_c , C_{ch} , $R_{term,TX}$, $R_{term,RX}$ that minimizes or maximizes N_p
 - It uses reactive stimulus technique choosing the next parameter set using a Bayesian optimization
 - With these added DPI functions:
 - **BAYESOPT_initialize()**
 - **BAYESOPT_selectNext()**
 - **BAYESOPT_updateModel()**
 - **BAYESOPT_getOptimum()**

```

class SEQ_MARGIN extends uvm_sequence #(PACKET);
`uvm_object_utils(SEQ_MARGIN)
...
task body();
  PKT = PACKET::type_id::create("PKT");
  opt_data = BAYESOPT_initialize(4, lower_bounds, upper_bounds);
  // with receiver present
  PKT.RX_present = 1;
  for (int i=0; i<=num_iter; i++) begin:LOOP1
    if (i < num_iter) BAYESOPT_selectNext(opt_data, var_value);
    else BAYESOPT_getOptimum(opt_data, var_value);
    PKT.Cc = var_value[0];
    PKT.Cch = var_value[1];
    PKT.Rterm_tx = var_value[2];
    PKT.Rterm_rx = var_value[3];
    start_item(PKT);
    finish_item(PKT);
    get_response(RSP);
    // find minimum Np when receiver is present
    BAYESOPT_updateModel(opt_data, var_value, RSP.Np);
  end: LOOP1
  // with receiver absent
  ...
endtask: body
endclass: SEQ_MARGIN

```

Fixture Module

- Fixture module uses a handshaking protocol to enable multiple N_p trials within one simulation run
 - It waits for the driver agent to assert ***START***;
 - Retrieves a new set of C_c , C_{ch} , $R_{term,TX}$, $R_{term,RX}$ values and a flag to connect RX;
 - Enables the RX detection circuit and waits for its response; and
 - Sends the N_p value back to the driver agent and assert ***DONE***

```

module FIXTURE (IF_t IF);
  // interface handshaking
  always begin: LOOP
    @(posedge IF.START);
    IF.DONE = 0;
    RX_present = IF.RX_present;
    Cc = IF.Cc;
    Cch = IF.Cch;
    Rterm_tx = IF.Rterm_tx;
    Rterm_rx = IF.Rterm_rx;

    EN = 0;
    #(t_init);
    EN = 1;
    fork
      @(posedge RXDET.CTRL.DONE);
      #(t_meas);
    join_any
    disable fork;

    IF.Np = (RXDET.CTRL.DONE) ? RXDET.CTRL.Np_val : -1;
    IF.DONE = 1;
  end: LOOP

```

Fixture Module (2)

- Testbench configurations include:
 - RX detection circuit (DUT)
 - TX driver with AC-coupled channel
 - RX front-end with ideal switches controlling its presence
 - Clock and supply sources
- Using ***cap_sw*** & ***res_sw*** primitives to change C_c , C_{ch} , $R_{term,TX}$, $R_{term,RX}$ as signals (i.e., not parameters) during simulation

```

// DUT model for the PCIe receiver detection circuit
rxdetect #( .VrefH(VrefH), .VrefL(VrefL), .Np_thres(1024))
    RXDET (.CK(CK), .TX_P(TX_P), .TX_N(TX_N),
            .EN(EN), .RXDETECT(RXDETECT));

// transmitter and AC-coupled channels
tx_PCIE TX (.out_p(TX_P), .out_n(TX_N), .vdd(VDD),
           .Rterm(Rterm_tx), .Cp(Cp_tx));
channel CHN_P (.port_1(CH_P), .port_2(RX_P), .Cch(Cch));
channel CHN_N (.port_1(CH_N), .port_2(RX_N), .Cch(Cch));
cap_sw CP (.pos(TX_P), .neg(CH_P), .C(Cc));
cap_sw CN (.pos(TX_N), .neg(CH_N), .C(Cc));

// add receiver depending on RX_present
bit_to_xbit RX_CONN (.in(RX_present), .out(RX_EN));
switch SW0 (.pos(RX_P), .neg(RX_P0), .ctrl(RX_EN));
switch SW1 (.pos(RX_N), .neg(RX_N0), .ctrl(RX_EN));
rx_PCIE RX (.in_p(RX_P0), .in_n(RX_N0),
            .Rterm(Rterm_rx), .Cp(Cp_rx));

// sources feeding clock and supply voltage
clk_gen #( .freq(f_clk)) XP0 (.out(CK0));
xbit_to_bit CK_CONN (.in(CK0), .out(CK));
dc_gen #( .value(vdd_val)) XP1 (.out(VDD));

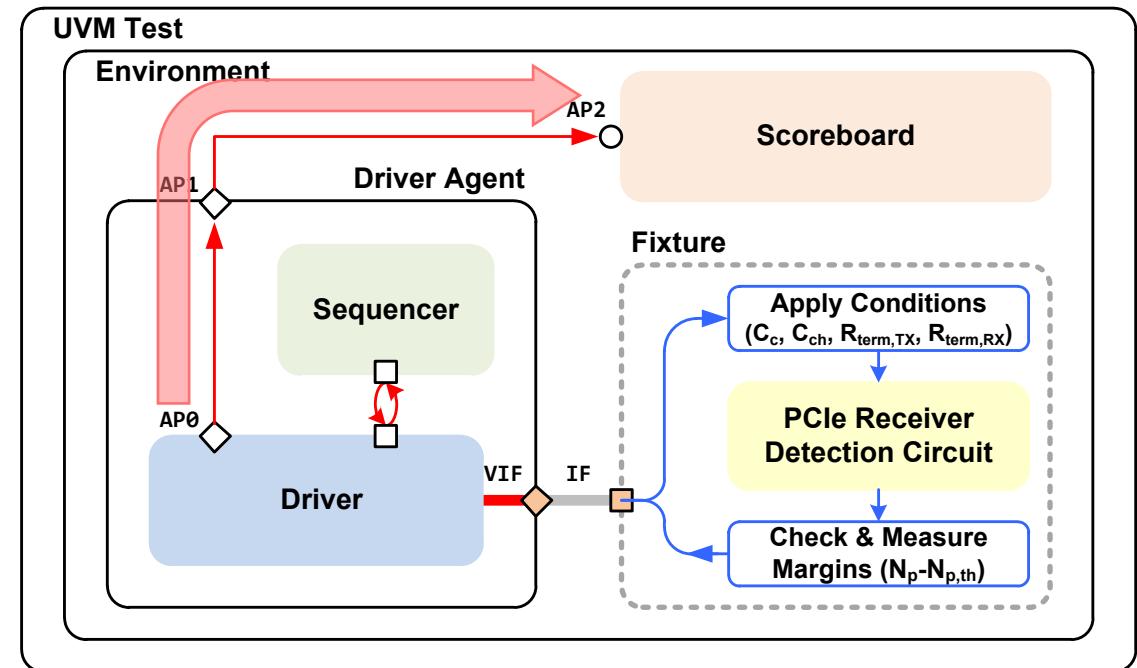
endmodule

```

Scoreboard Component

- It listens to all the N_p results broadcast by the driver agent and keeps track of $\min(N_{p,w/RX})$ & $\max(N_{p,w/oRX})$
- And reports these values when the simulation is finished

Min N_p with RX present = 2507
 Max N_p with RX absent = 223



Experimental Results: Measuring N_p

- Collecting $\min(N_{p,w/RX})$ & $\max(N_{p,w/oRX})$ for various V_{refH} & V_{refL} values
- Each simulation takes about 90 seconds to complete 400 iterations

V_{refL}	V_{refH}	1.700	1.725	1.750	1.775
1.400		(15, 151)	(29, 175)	(55, 203)	(1187, 255)
1.375		(15, 167)	(36, 183)	(663, 215)	(3791, 259)
1.350		(27, 179)	(499, 199)	(2507, 223)	(4095, 271)
1.325		(355, 207)	(1959, 223)	(3851, 247)	(4095, 283)
1.300		No Oscillations	No Oscillations	No Oscillations	No Oscillations

Experimental Results: Design Margins

- Design margin is calculated as ($\min(N_{p,w/RX}) - \max(N_{p,w/oRX})$) / 2
- Design margin is highly sensitive to the variations in V_{refH} and V_{refL}

V_{refL}	V_{refH}	1.700	1.725	1.750	1.775
1.400		-68	-73	-74	466
1.375		-76	-73	224	1766
1.350		-76	125	1142	1912
1.325		64	868	1802	1906
1.300		-	-	-	-

Summary

- A UVM testbench for characterizing the design margins of an analog/mixed-signal circuit is presented
- The testbench finds the worst-case deviation of the circuit's response across a continuous-valued parameter space by:
 - Using *XMODEL* primitives to model the analog components of a PCIe receiver detection circuit at the device level; and
 - Combining a reactive stimulus technique with a Bayesian optimization algorithm to efficiently and adaptively explore the parameter space
- This work paves the way for adaptive, coverage-driven AMS verification